



integrated circuit defect fault semiconductor ar

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**Patents** Patents 1 - 14 on **integrated circuit defect fault semiconductor analysis power supply**. (0.06 sec)

Selectable **power supply** lines for isolating defects in **integrated circuits**

US Pat. 6043672 - Filed May 13, 1998 - LSI Logic Corporation

Certain sections of an **integrated circuit**, such as sections in the same region of an **integrated circuit**, often share common (or unitary) **power supply** lines. ...

**Semiconductor integrated circuit** device incorporating fuse-programmable pass/fail identification ...

US Pat. 5768290 - Filed Apr 1, 1997 - Mitsubishi Denki Kabushiki Kaisha

23. between the node to which external **power supply** voltage the **semiconductor integrated circuit** device determined to be signal of inverter circuit 76 at ...

**Integrated circuit** fault testing implementing voltage **supply** rail pulsing and corresponding ...

US Pat. 5483170 - Filed Aug 24, 1993 - New Mexico State University Technology Transfer Corp.

Background Art The complexity of **integrated circuit** testing is rapidly 15 ...

"**Power Supply** Current Signature (PSCS) Analysis: A New Approach to System ...

**IDDQ** testing of **integrated circuits**

US Pat. 5757816 - Filed Oct 24, 1996 - Advanced Micro Devices, Inc.

Many of those faults cause elevated quiescent **power supply** current (IDDQ), ... words manufactured by Philips, using Inductive **Fault Analysis** technique. ...

Diagnostic system analyzing frequency spectrum of electric **power** for diagnosing **integrated** ...

US Pat. 6058502 - Filed Sep 1, 1998 - NEC Corporation

The **fault** product contained a static **defect** nosis system; associated with the component transistor, by way of **semiconductor integrated circuit** device; ...

**Fault** block detecting system using abnormal current

US Pat. 5850404 - Filed Jun 6, 1997 - NEC Corporation

Thus, generally, if a **semiconductor** device such as a CMOS device has a physical **defect** therein, an abnormal quiescent VDD **supply** current flows therethrough ...

Device for the bus-networked operation of an electronic unit with microcontroller, and its use

US Pat. 5892893 - Filed Mar 26, 1997 - Mercedes Benz AG

-inn- rj^ -i u- ua unit is switched off. combined to form function blocks; ...  
the **integrated semiconductor circuit** 100 in FIG. ...

Separate I.sub.DDQ -testing of signal path and bias path in an IC

US Pat. 5625300 - Filed Dec 14, 1994

A leakage or substrate for **supply** of the **circuit** and with a biasing node for ... has shown a lot of promise in the **analysis circuit's** functional operation, ...

**Fault** block detecting system using abnormal current and abnormal data output

US Pat. 5864566 - Filed Nov 14, 1997 - NEC Corporation

Simultaneously, the control **circuit 9** monitors a quiescent VDD **supply** current  $I_{DDQ}$   
... the **fault** point P 50 propagates through the **semiconductor** device. ...

**Integrated injection logic circuit with test pads on injector common line**

US Pat. 4489247 - Filed Feb 17, 1982 - Tokyo Shibaura Denki Kabushiki Kaisha  
In the wafer state, the good and ments in or on a **semiconductor** substrate is ...  
In the faults **analysis** of the **integrated circuit** the number of Pads must be ...

**Method and apparatus for pattern recognition of wafer test bins**

US Pat. 5787190 - Filed Jun 27, 1997 - Advanced Micro Devices, Inc.  
\*ui \_ ^ i sequence, comprising where a **power supply** short test, toads the bin summary  
... A **fault** pattern (hat layer strip back, hot spot, chemical **analysis**, ...

**Apparatus and method for testing of integrated circuits**

US Pat. 5726997 - Filed May 22, 1995  
**Power** is tions in the quiescent  $I_{DD}$  current can indicate a **fault circuit** distributed  
to the internal **power** busses 14 by **supply** busses SUMMARY OF THE ...

**Current signatures for IDDQ testing**

US Pat. 6175244 - Filed Apr 25, 1997 - Carnegie Mellon University  
Robert C. Aitken, "A Comparison of **Defect** Models for **Fault** Location with ...  
and Charles F. Hawkins, "Measurements of Quiescent **Power Supply** Current for ...

**Semiconductor integrated circuit**

US Pat. 6119250 - Filed May 22, 1998 - Matsushita Electric Industrial Co., Ltd.  
Accordingly, this invention provides a **semiconductor integrated circuit** capable  
of **circuit** block evaluation, **fault analysis**, and other similar operations. ...

integrated circuit defect fault semiconductor a

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## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	109	defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:48
S2	63	analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:49
S3	0	transient power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50
S4	51	power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 17:00
S5	40	fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S6	40	current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50
S7	37	potential AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51

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S8	9	voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S9	9	current AND voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51